

**Notice of References Cited**

Application/Control No.

09/659,779

Applicant(s)/Patent Under  
Reexamination  
OGURO, TOSHIHARU

Examiner

Kim T. Huynh

Art Unit

2112

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
<input checked="" type="checkbox"/>	A	US-6,434,744	08-2002	Chamberlain et al.	717/168
<input checked="" type="checkbox"/>	B	US-6,438,749	08-2002	Chamberlain, Benjamin C.	717/174
<input checked="" type="checkbox"/>	C	US-6,141,705	10-2000	Anand et al.	710/15
<input checked="" type="checkbox"/>	D	US-6,205,498	03-2001	Habusha et al.	710/29
<input checked="" type="checkbox"/>	E	US-6,067,628	05-2000	Krithivas et al.	713/340
<input checked="" type="checkbox"/>	F	US-6,260,091	07-2001	Jayakumar et al.	710/113
<input checked="" type="checkbox"/>	G	US-6,009,490	12-1999	Fukui et al.	710/113
<input checked="" type="checkbox"/>	H	US-5,822,520	10-1998	Parker, Steven D.	709/230
<input checked="" type="checkbox"/>	I	US-6,771,664	08-2004	Garney et al.	370/474
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.